

Advanced Search

Go

About Us

Advances in OptoElectronics

Journal Menu

Abstracting and Indexing Aims and Scope Article Processing Charges Author Guidelines **Bibliographic Information Contact Information** Editorial Board Editorial Workflow Reviewers Acknowledgment Subscription Information

Open Special Issues **Closed Special Issues** Published Special Issues Special Issue Guidelines

> Call for Proposals for Special Issues

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Research Article

nm- and µm-Scale Surface Roughness on Glass with Specific Optical Scattering Characteristics on Demand

Abstract

Full-Text PDF

Linked References

How to Cite this Article

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Abstract

During maskless ion etching of amorphous glass, self-organization can arise in certain etch parameter ranges, which leads to dense-lying dots/cones with typical diameters and heights in the 30-300nm range. Another phenomenon, which results in cone sizes around $1\,\mu m$ or more, is self-masking especially in the case of heterogeneous glasses like borosilicate glass as used in this contribution. Thus, a wide range of characteristic sizes and shapes of individual scatterers on the glass surface, jointly acting as a defined roughness, can be achieved resulting in specific optical scattering characteristics. This contribution gives results on borosilicate thinglass dry etching. Certain surface morphologies are reported together with experimental results on their optical scattering characteristics.

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